

Technical Data

NCC Series



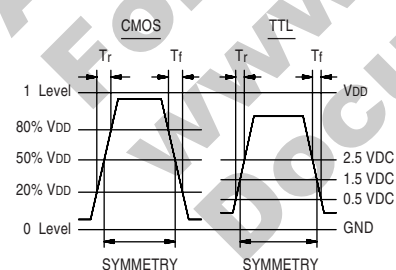
Description

A crystal controlled, low current hybrid oscillator providing precise rise and fall times to drive CMOS and NMOS micro-processors. Compatible with both CMOS and TTL. Can drive up to 2 LSTTL loads. Device is packaged in 14-pin or an 8-pin DIP compatible full size or half size, resistance welded, all metal case. Pin 7 (pin 4 for 1/2 size) is grounded to the case to reduce RFI.

Applications & Features

- Low power
- CMOS and TTL compatible output
- Grounded, all metal full size and half size case
- See NTH Series for Tri-State on pin 1
- Gull Wing packages compatible with standard reflow processes

Output Waveform



Frequency Range:	500 kHz to 24 MHz
Frequency Stability:	±25, ±50 or ±100 ppm over all conditions: calibration tolerance, operating temperature, input voltage change, load change, *aging, shock and vibration.
*Aging	30 days
Temperature Range:	
Operating:	0°C to +70°C
Storage:	-55°C to +125°C
Supply Voltage:	
Recommended Operating:	5V ±10%
Supply Current:	(See Input Current vs. Frequency Graph, page 2)
Output Drive:	
CMOS	
Symmetry	see part numbering guide
Rise & Fall Times:	12ns max, 20% to 80% VDD
Logic 0:	10% VDD max
Logic 1:	90% VDD min
Output Load:	2 CMOS
TTL	
Symmetry	see part numbering guide
Rise & Fall Times:	12ns max, 0.5V to 2.5V
Logic 0:	0.5V max
Logic 1:	2.5V min (VCC -0.6 typ)
Output Load:	2 LSTTL
Mechanical:	
Shock:	MIL-STD-883, Method 2002, Condition B
Solderability:	MIL-STD-883, Method 2003
Terminal Strength:	MIL-STD-883, Method 2004, Condition B2
Vibration:	MIL-STD-883, Method 2007, Condition A
Solvent Resistance:	MIL-STD-202, Method 215
Resistance to Soldering Heat:	MIL-STD-202, Method 210, Condition A, B or C
Environmental:	
Gross Leak Test:	MIL-STD-883, Method 1014, Condition C
Fine Leak Test:	MIL-STD-883, Method 1014, Condition A2
Thermal Shock:	MIL-STD-883, Method 1011, Condition A
Moisture Resistance:	MIL-STD-883, Method 1004

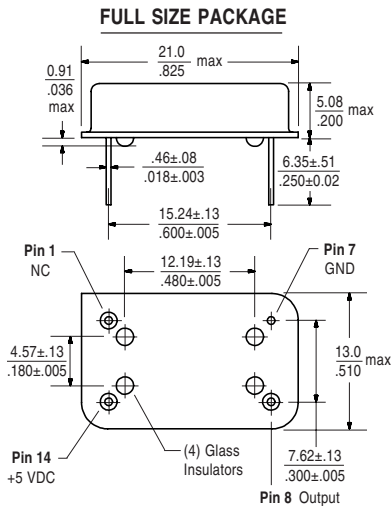
Part Numbering Guide

Series	NCC 0 6 0 C	Frequency (MHz)	- 4.0000
Symmetry & Temperature Range		Blank	= No Enable/Disable
0	= 40/60% max, 0 to 70°C	Stability Tolerance	
2	= 40/60% max, -40 to 85°C	A	= ±25 ppm, 0 to +70°C only
4	= 45/55% max, -40 to 85°C, TTL to 7.1590MHz	B	= ±50 ppm
6	= 45/55% max, 0 to 70°C, TTL to 7.1590MHz	C	= ±100 ppm
A	= 45/55% max, 0 to 70°C, CMOS to 7.1590MHz	Package Type	
C	= 45/55% max, -40 to 85°C, CMOS to 7.1590MHz	0	= Full Size
		9	= Half Size
		K	= Full Size, Gull Wing
		J	= Half Size, Gull Wing
Frequency Range			
3	= 500 kHz ~ 3.9999 MHz		
6	= 4 MHz to 24 MHz		

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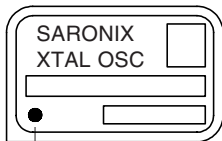
NCC Series

Package Details



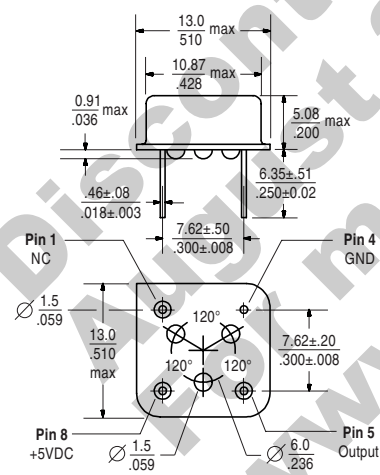
Marking Format *

Includes Date Code, Frequency & Model



Denotes Pin 1

HALF SIZE PACKAGE



Marking Format *

Includes Date Code, Frequency & Model

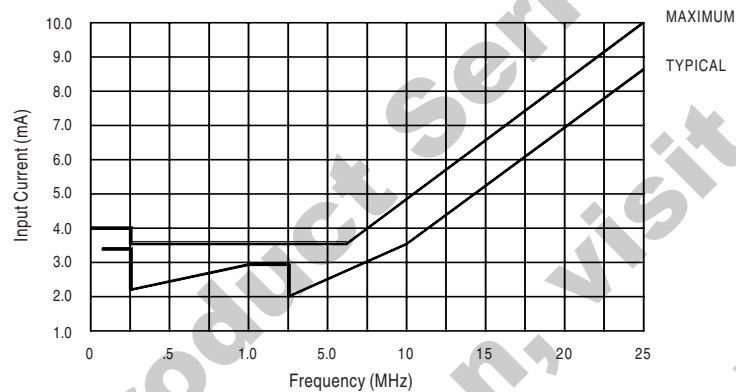


Denotes Pin 1

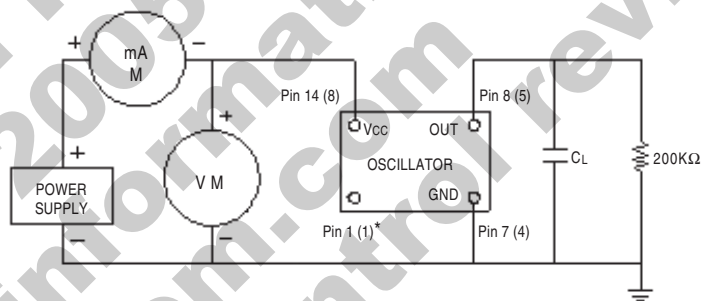
* Exact location of items may vary

Scale: None (Dimensions in mm/inches)

Input Current vs. Frequency at +5.0V



Test Circuits



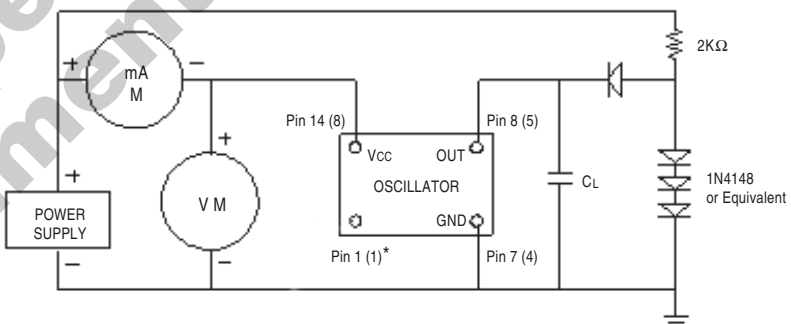
NOTE:

$C_L = 15 \text{ pF}$ max (Includes probe and fixture capacitance)

Pin 1 = No connection.

* () Indicates pin numbers for half-size package

CMOS TEST CIRCUIT



NOTE:

$C_L = 15 \text{ pF}$ max (Includes probe and fixture capacitance)

Pin 1 = No connection.

* () Indicates pin numbers for half-size package

TTL TEST CIRCUIT

All specifications are subject to change without notice.

DS-133 REV D